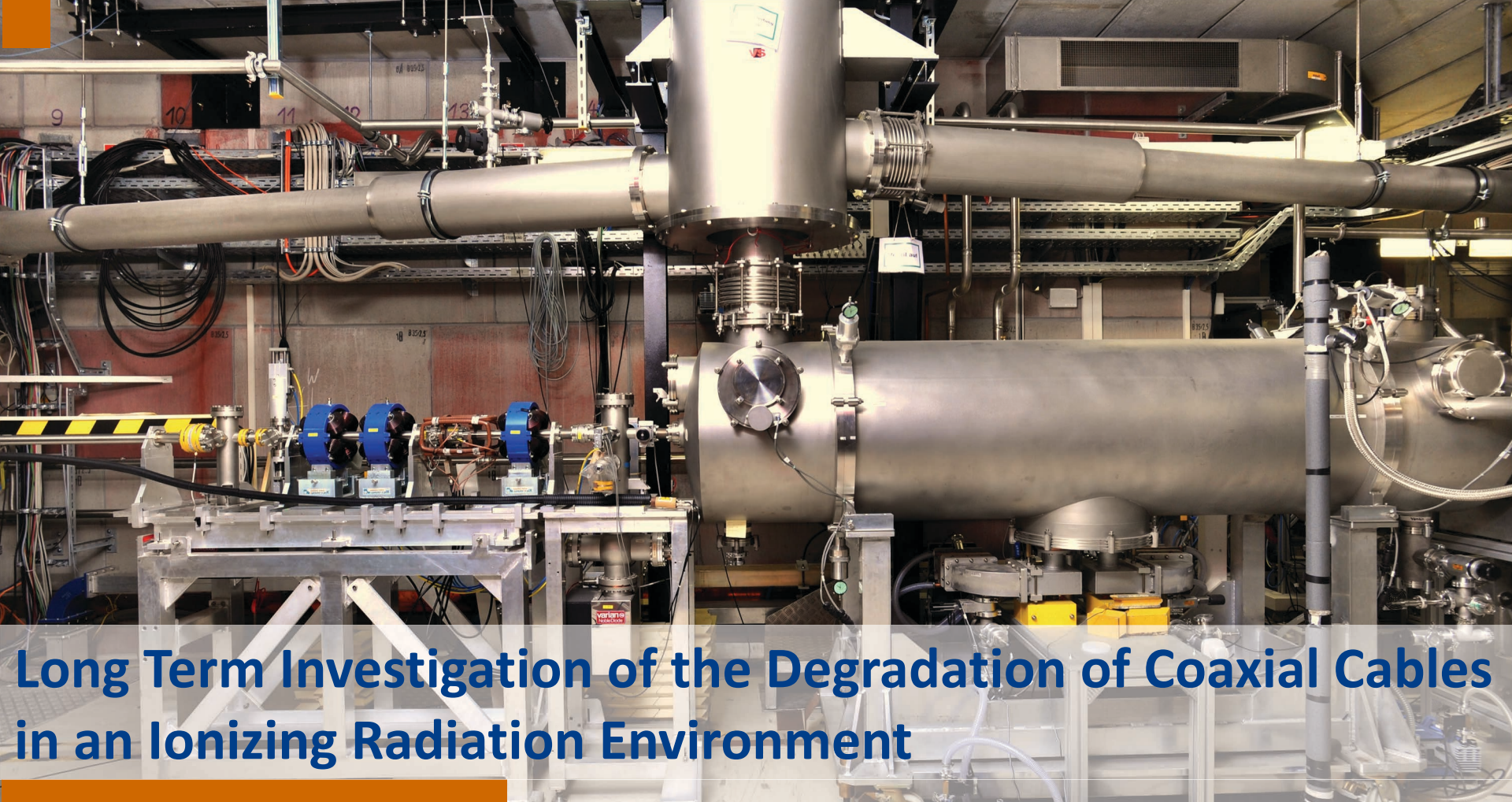
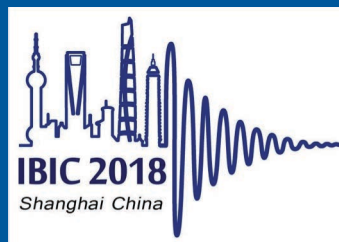




Long Term Investigation of the Degradation of Coaxial Cables in an Ionizing Radiation Environment

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ELBE

- Short introduction

Motivation

- CW Accelerator environment
- Broadband BAM measurement

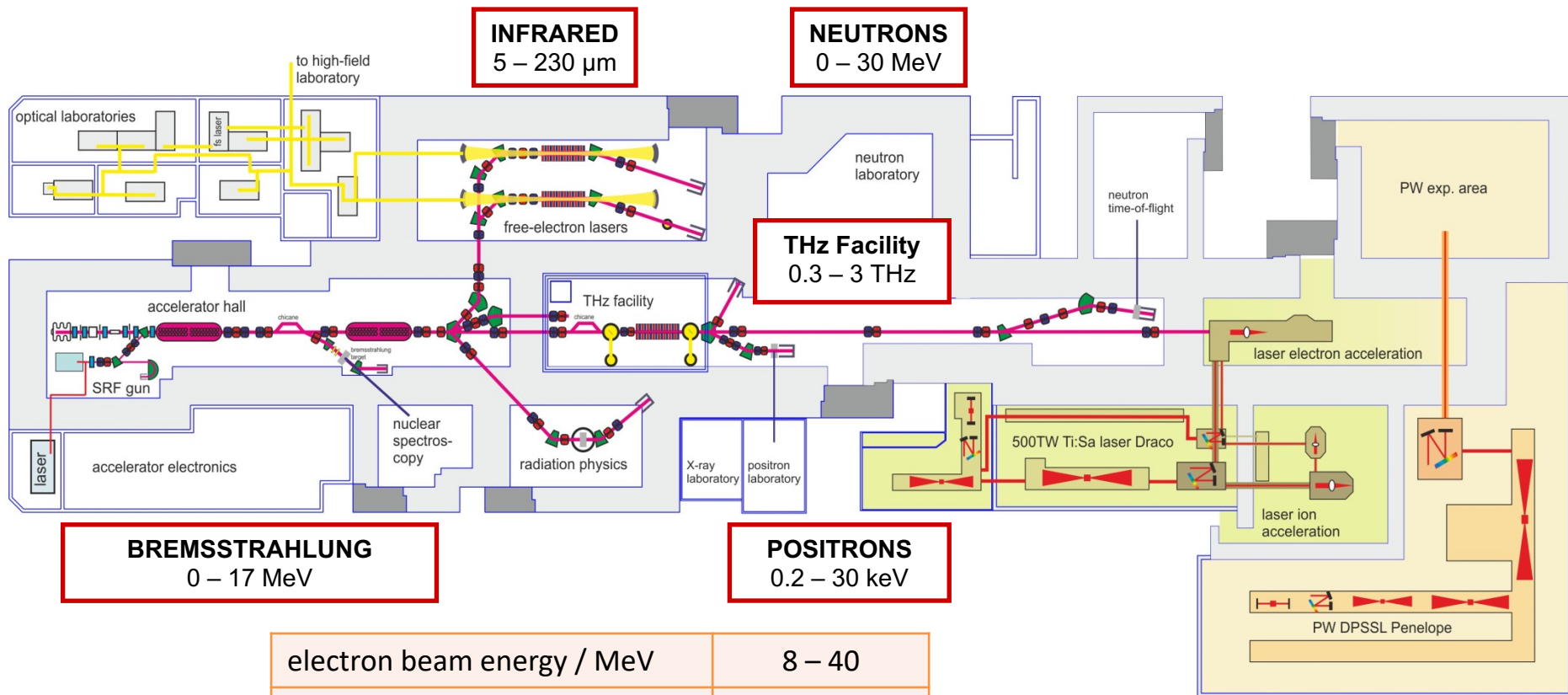
Measurement setup

- Mapping of radiation field
- S-parameter measurement

Long term measurement and results

- Dose measurement
- Degradation documentation
- Determination of the loss factors

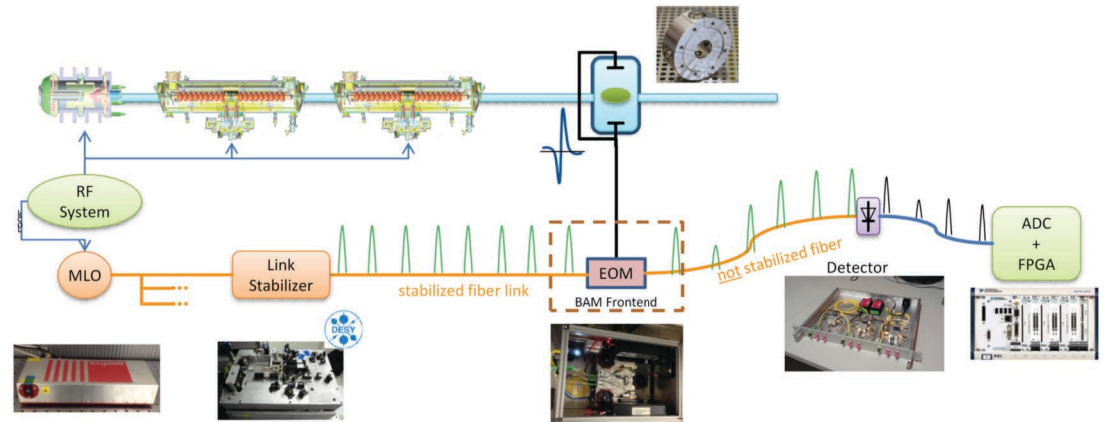
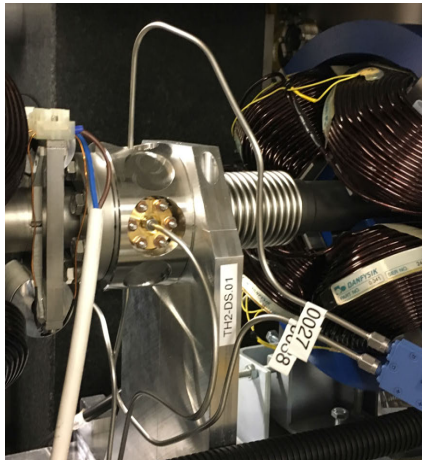
Summary and outlook



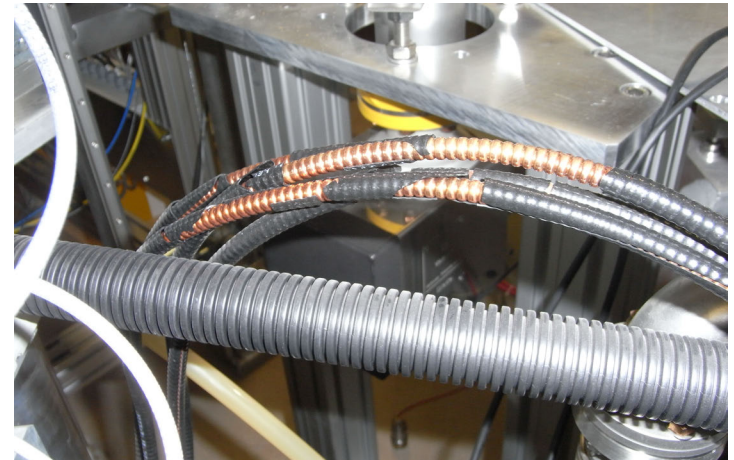
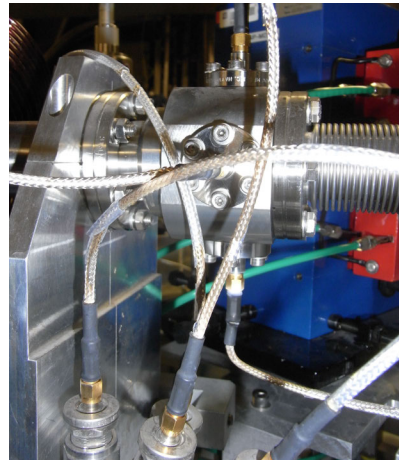
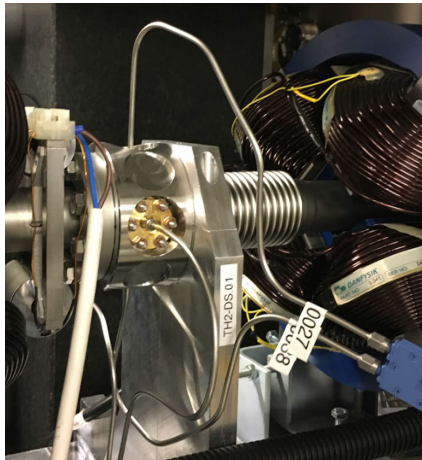
electron beam energy / MeV	8 – 40
average cw beam current / μA	1600
bunch charge / pC	
- thermionic injector	100
- SRF photo injector	300 (1000)
minimal Bunch length/ ps	0.2

allowed beam loss: $\leq 10 \mu\text{A}$

- beam loss up to 10 μA generates Bremsstrahlung on the Gray/minute (Gy/min) level
- for high accuracy arrival time measurements cables with high bandwidth (40 GHz) and low insertion (IL) loss are required
- limited data for high bandwidth applications in ionizing radiation fields available

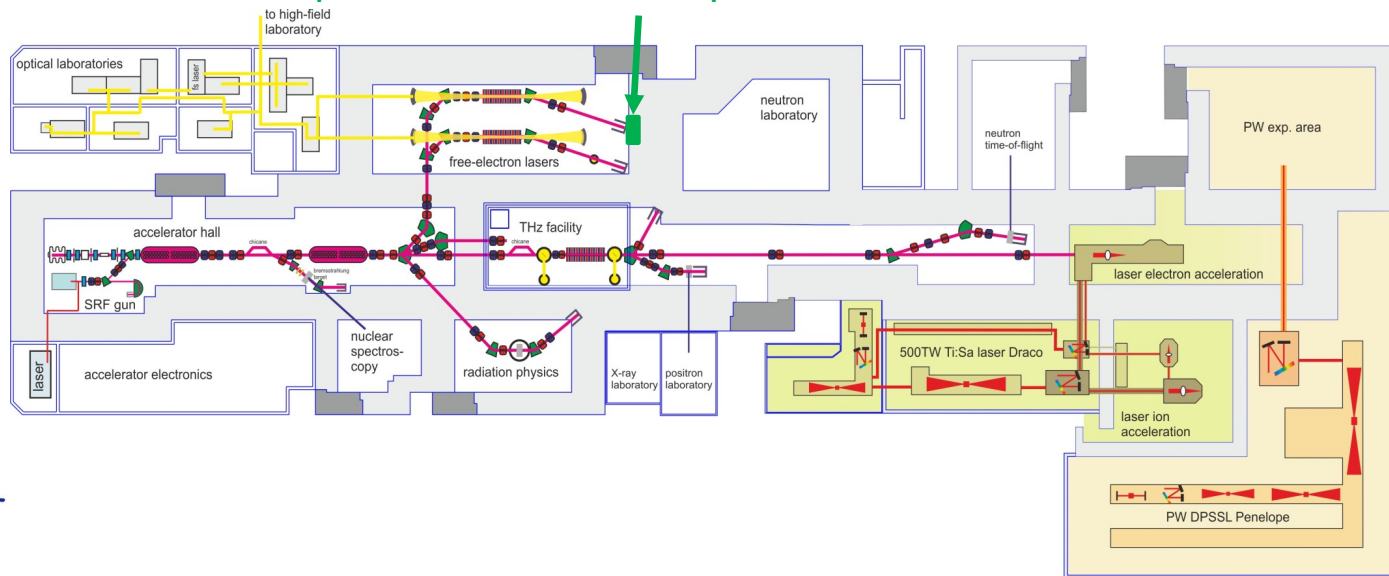


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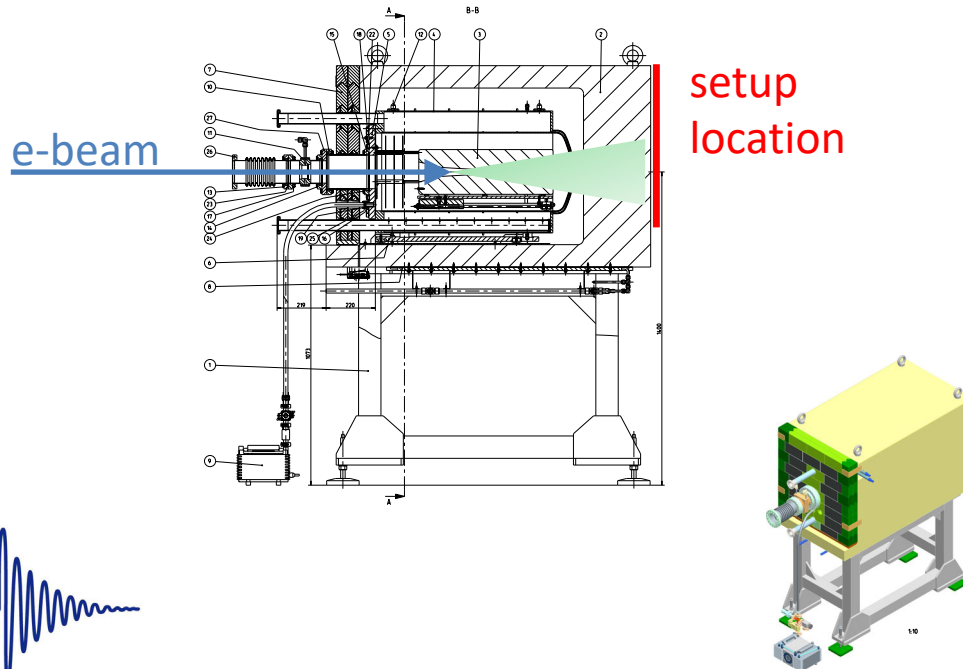


- Setup of a test-stand to acquire the necessary data in a reasonable time frame
- Questions to be answered:
 - Can a PTFE-based cable be used in such an environment for a long time?
 - How does the radiation effects the spectral response of a cable?
 - Are there differences between cable types made of the same/ or similar materials?

Test setup behind beam dump of U100 undulator



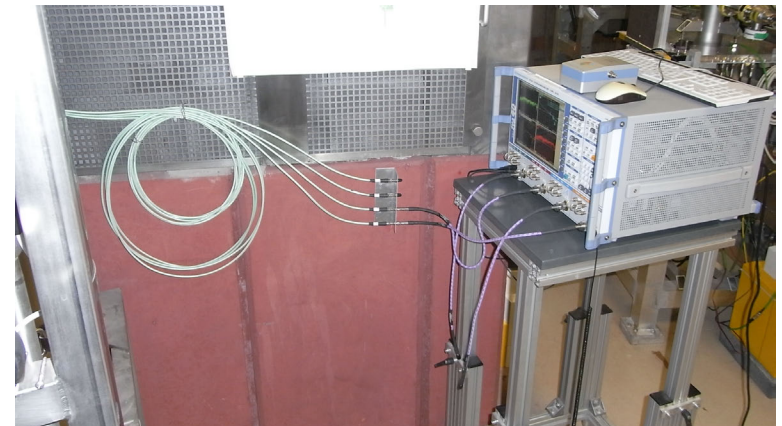
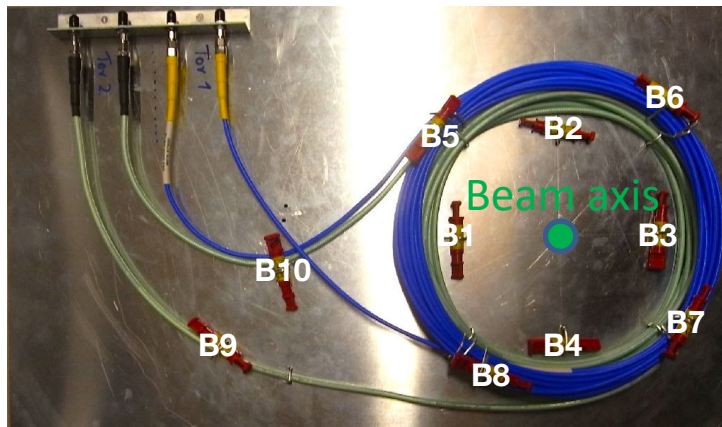
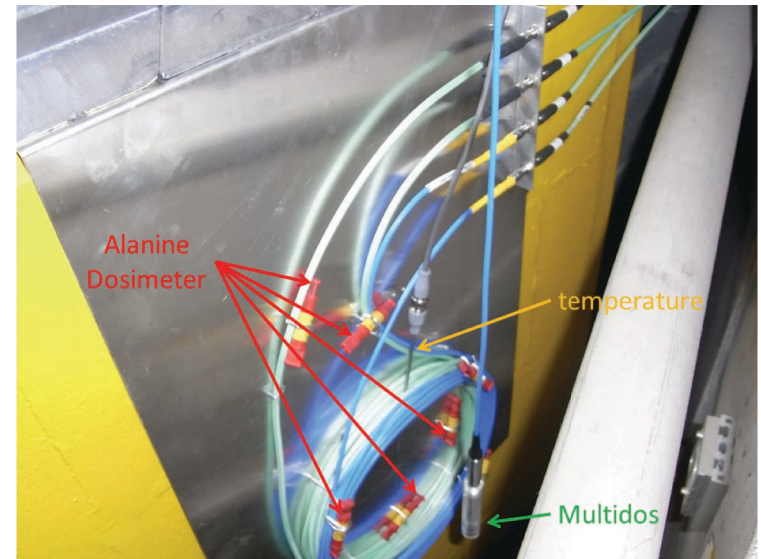
- parasitic setup behind FEL-dump
- devices under test can be mounted on dedicated aluminum plate
- preliminary coarse dose mapping performed for 3 months
- maximum dose of 19.2 kGy on beam axis



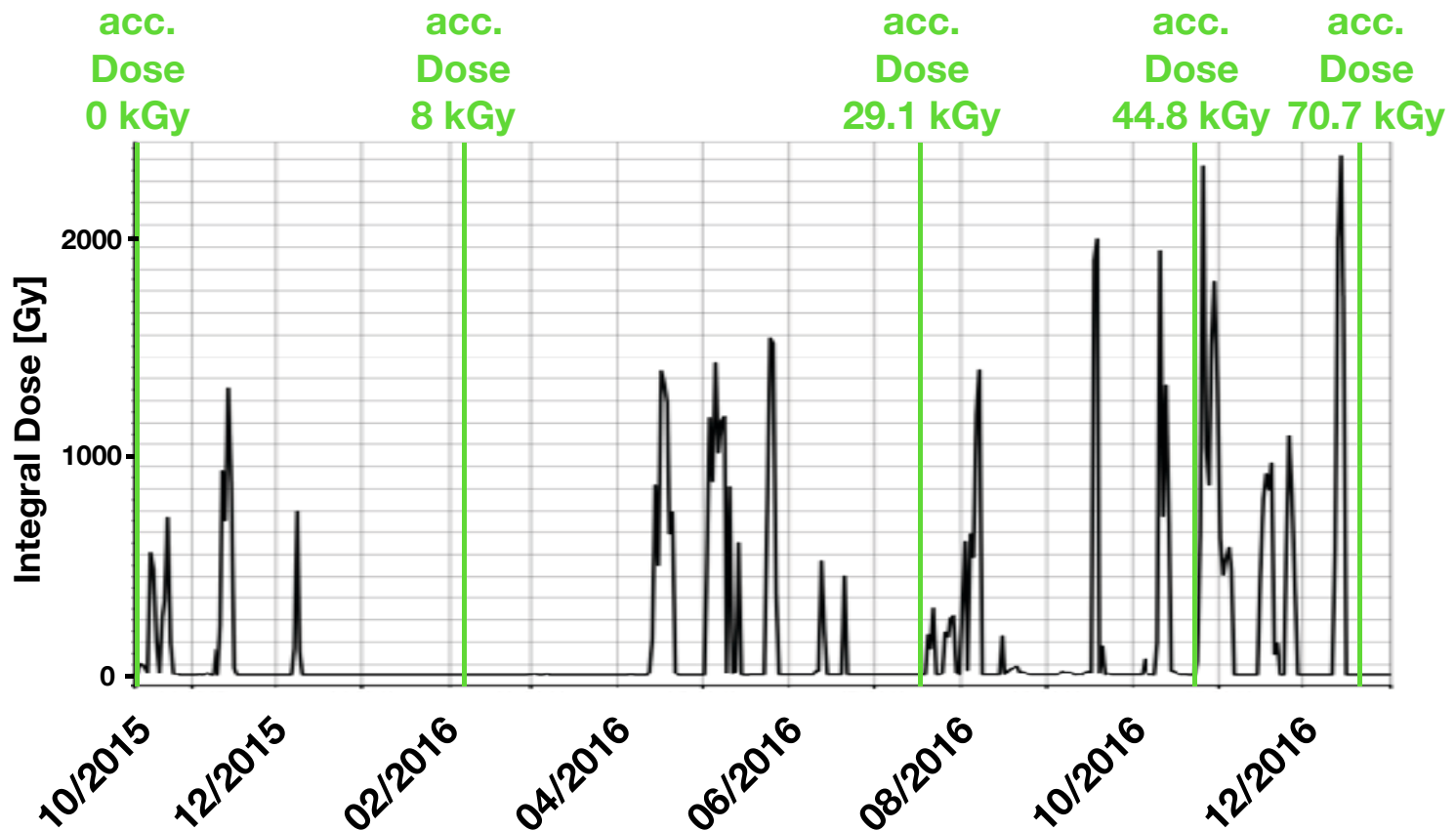
Results dose mapping



- 10 alanine dosimeters for post mortem analysis of total dose
- 1 Multidos probe for online dose measurement
- temperature probe
- two types of cable
 - Cable under test 1 (CUT1, 8 m, blue)
 - Cable under test 2 (CUT2, 10 m, green)
- connection to patch panel
- S-parameter measurements

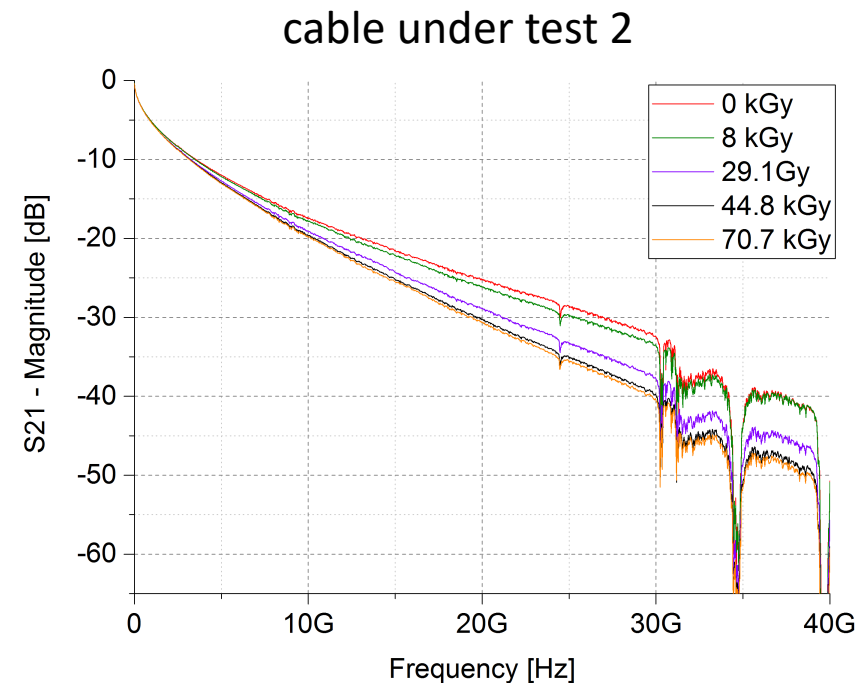
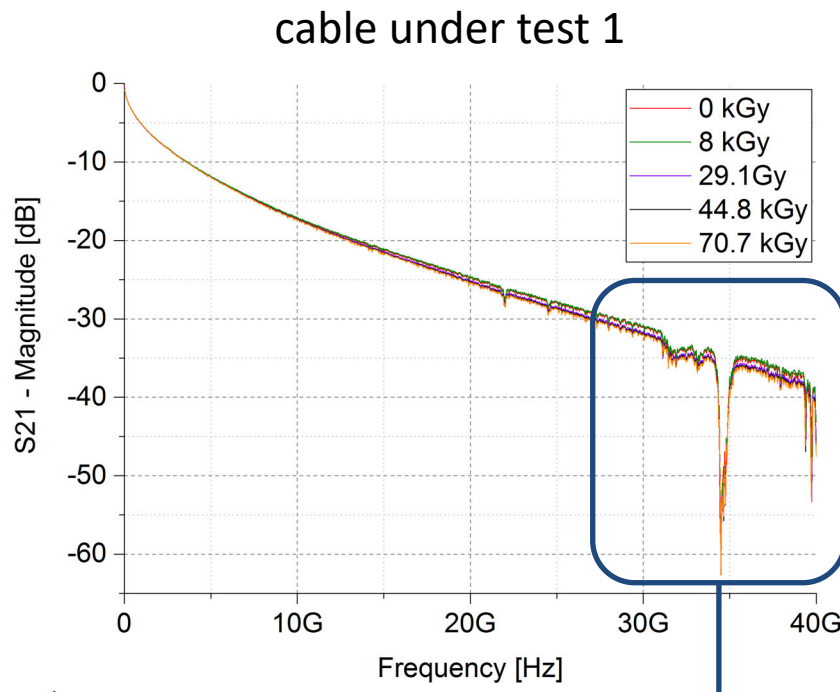


- single radiation probe (Multidos)
- after significant dose accumulation, S-parameters measurement

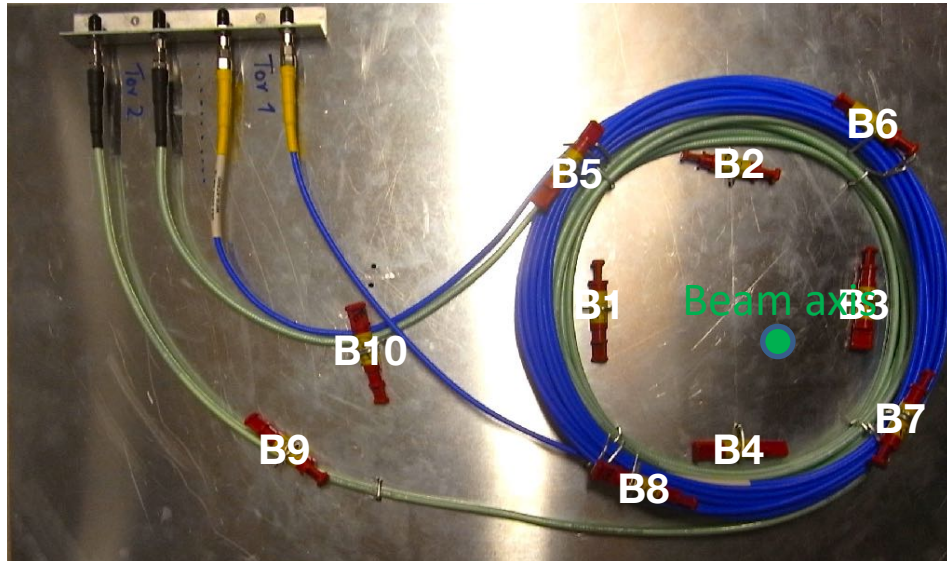


S-parameter measurement results

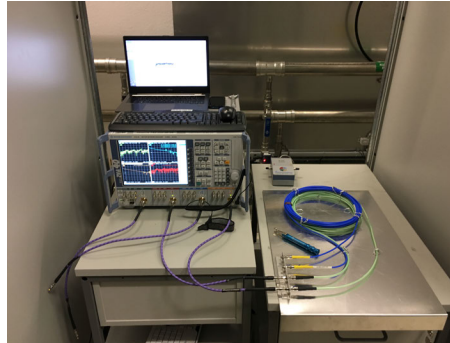
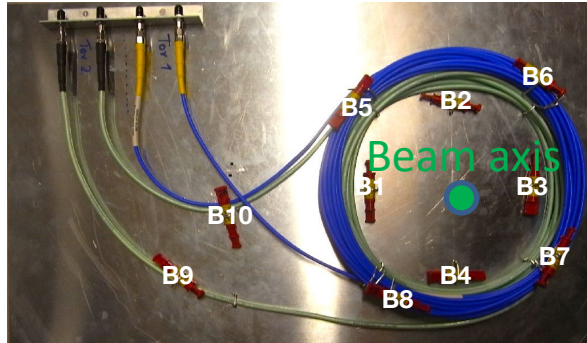
- dose dependent degradation could be measured
- cable under test showed higher level degradation



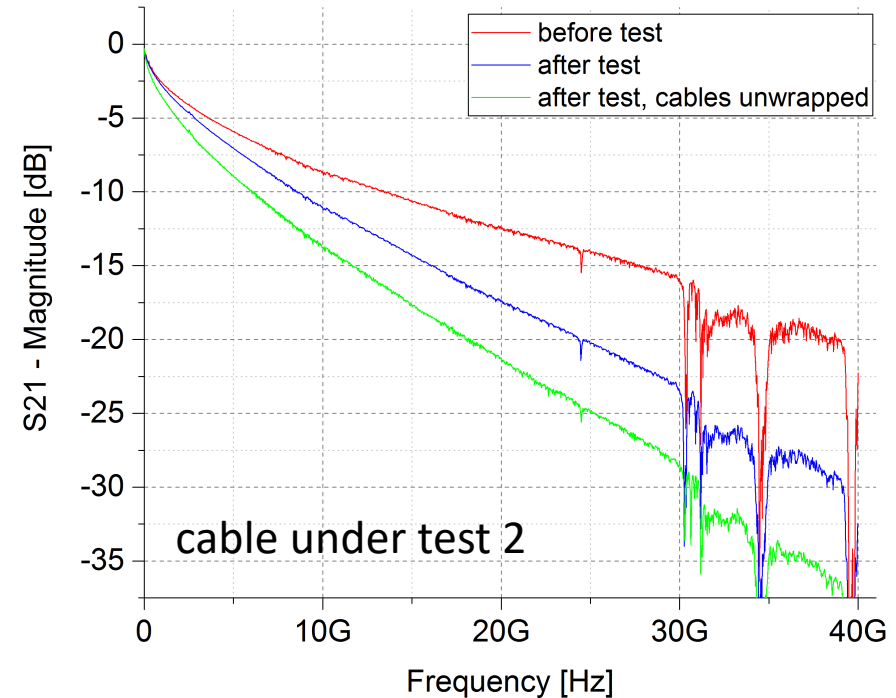
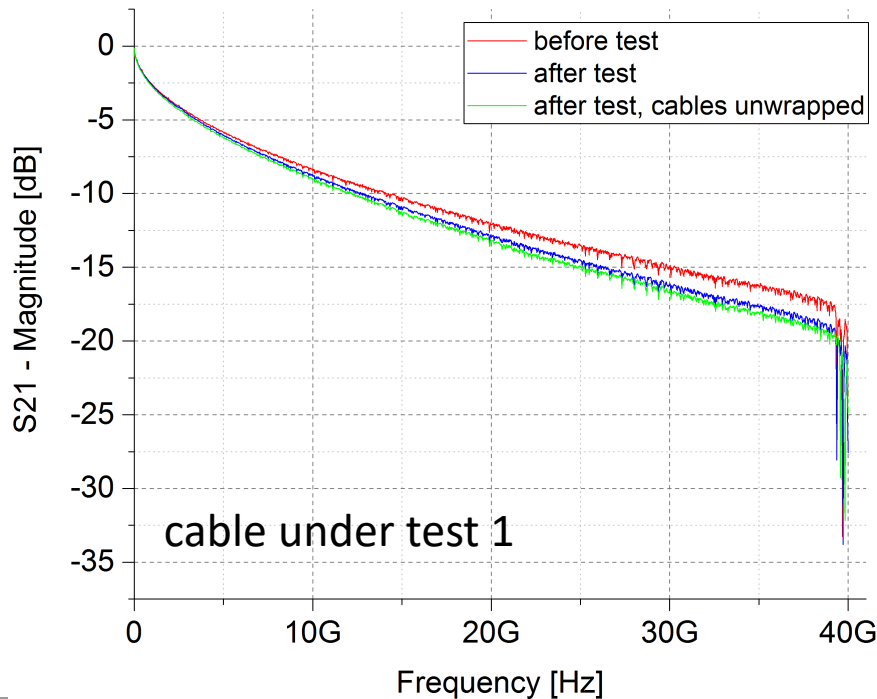
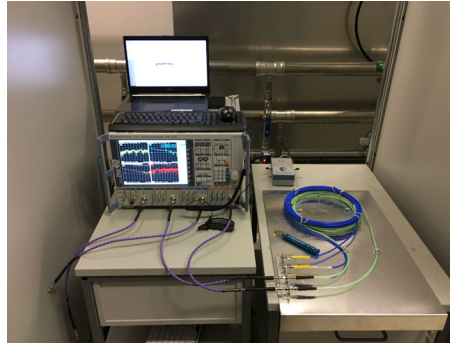
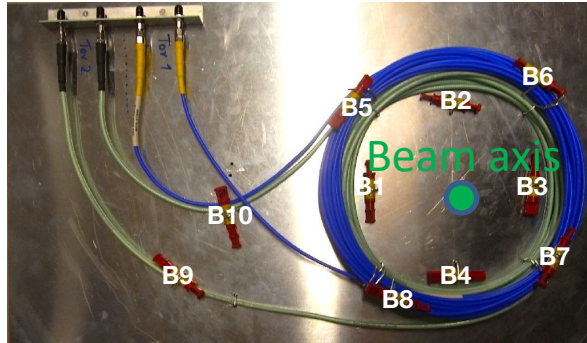
Notches introduced by patch cables
(cable under test 2 – type)



Name	Accumulated Dose
B1	64.28 kGy
B2	51.36 kGy
B3	93.85 kGy
B4	83.66 kGy
B5	30.38 kGy
B6	29.52 kGy
B7	57.85 kGy
B8	43.81 kGy
B9	9.40 kGy
B10	13.80 kGy



- S-parameter measurements performed using vector network analyzer
 - before installation and irradiation, mounted on sample plate
 - after installation and irradiation, mounted on sample plate
 - after (carefully) unwinding the cables



- Insertion loss is defined by resistive (K1) and dielectric (K2) losses

$$IL(f) = K1 \cdot \sqrt{f} + K2 \cdot f$$

	K1	K2
CUT1 before test	0.313	0.0053
CUT1 after test	0.319	0.0099
CUT1 unwound	0.319	0.0099
CUT2 before test	0.249	0.0066
CUT2 after test	0.250	0.0308
CUT2 unwound	0.250	0.0340

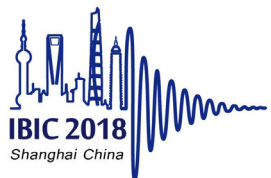
- while the resistive losses stay nearly the same, the dielectric losses are increasing
- cable under test 2 was much more sensitive to mechanical stress than before

- parasitic cable characterization in radiation environment successful done
- measurements showed significant differences between two PTFE-dielectric cables
- cable under test 1 showed very good RF properties and radiation hardness and will be used for bunch arrival time setup in future
- investigations ongoing on the sources of this differences
- Setup can be used to characterize further pieces of equipment that is going to be installed close to the beam line

Thank you.



Acknowledgement: I. Kösterke, M. Freitag, B. Reppe



Whitepaper:

<http://www.testkabel.webseiten.cc/index.php?id=10>

